

040635

REVISIONS																			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED																
B	Convert to military drawing format. Add vendor CAGE no. 27014 to case 2. Add terminal connections for case 2 to figure 1.	1988 FEB 05	<i>May 88</i>																

CURRENT CAGE CODE 67268

REV																				
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REV STATUS OF SHEETS	REV	B	B	B	B	B	B	B	B	B	B	B	B	B	B	B				
	SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13	14					

PMIC N/A STANDARDIZED MILITARY DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE AMSC N/A	PREPARED BY <i>James C. Jamison</i> CHECKED BY <i>DA Di Enzo</i> APPROVED BY <i>Michael Dwyer</i> DRAWING APPROVAL DATE 5 October 1984 REVISION LEVEL B	DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 MICROCIRCUITS, DIGITAL, HIGH-SPEED CMOS DUAL 2-BIT TRANSPARENT LATCH MONOLITHIC SILICON <table style="width: 100%; border: none;"> <tr> <td style="border: none; width: 15%;">SIZE A</td> <td style="border: none; width: 35%;">CAGE CODE 14933</td> <td style="border: none; width: 50%;">84070</td> </tr> <tr> <td colspan="3" style="border: none; text-align: center;">SHEET 1 OF 14</td> </tr> </table>	SIZE A	CAGE CODE 14933	84070	SHEET 1 OF 14		
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SEP 87

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5962-E767

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:

84070	01	E	X
-----	-----	-----	-----
Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510

1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	54HC75	Dual 2-bit transparent latch

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
E	D-2 (16-lead, .840" x .310" x .200"), dual-in-line package
F	F-5 (16-lead, .440" x .285" x .085"), flat package
2	C-2 (20-terminal, .358" x .358" x .100"), square chip carrier package

1.3 Absolute maximum ratings. 1/

Supply voltage range - - - - -	-0.5 V dc to +7.0 V dc
DC input voltage - - - - -	-0.5 V dc to $V_{CC} + 0.5$ V dc
DC output voltage - - - - -	-0.5 V dc to $V_{CC} + 0.5$ V dc
Clamp diode current - - - - -	± 20 mA
DC output current (per pin) - - - - -	± 25 mA
DC V_{CC} or GND current (per pin) - - - - -	± 50 mA
Storage temperature range - - - - -	-65°C to +150°C
Maximum power dissipation (P_D) - - - - -	500 mW 2/
Lead temperature (soldering, 10 seconds) - - - - -	+260°C
Thermal resistance, junction-to-case (θ_{JC}):	
Cases E, F, and 2 - - - - -	(see MIL-M-38510, appendix C)
Junction temperature (T_J) - - - - -	+175°C

1/ Unless otherwise specified, all voltages are referenced to ground.

2/ For $T_C = +100^\circ\text{C}$ to $+125^\circ\text{C}$, derate linearly at 12 mW/°C.

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1.4 Recommended operating conditions.

Supply voltage range - - - - -	+2.0 V dc to +6.0 V dc
Case operating temperature range - - - - -	-55°C to +125°C
Input rise or fall time:	
V _{CC} = 2.0 V- - - - -	0 to 1,000 ns
V _{CC} = 4.5 V- - - - -	0 to 500 ns
V _{CC} = 6.0 V- - - - -	0 to 400 ns
Minimum setup time, data to enable (t _S): <u>3/</u>	
At +25°C:	
V _{CC} = 2.0 V- - - - -	100 ns
V _{CC} = 4.5 V- - - - -	20 ns
V _{CC} = 6.0 V- - - - -	17 ns
At -55°C to +125°C:	
V _{CC} = 2.0 V- - - - -	150 ns
V _{CC} = 4.5 V- - - - -	30 ns
V _{CC} = 6.0 V- - - - -	26 ns
Minimum enable pulse width (t _W): <u>3/</u>	
At +25°C:	
V _{CC} = 2.0 V- - - - -	80 ns
V _{CC} = 4.5 V- - - - -	16 ns
V _{CC} = 6.0 V- - - - -	14 ns
At -55°C to +125°C:	
V _{CC} = 2.0 V- - - - -	120 ns
V _{CC} = 4.5 V- - - - -	24 ns
V _{CC} = 6.0 V- - - - -	21 ns
Minimum hold time, enable to data (t _H): <u>3/</u>	
At +25°C:	
V _{CC} = 2.0 V- - - - -	25 ns
V _{CC} = 4.5 V- - - - -	5 ns
V _{CC} = 6.0 V- - - - -	5 ns
At -55°C to +125°C:	
V _{CC} = 2.0 V- - - - -	40 ns
V _{CC} = 4.5 V- - - - -	8 ns
V _{CC} = 6.0 V- - - - -	7 ns

2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

3/ See figure 3.

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2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table and logic diagram. The truth table and logic diagram shall be as specified on figure 2.

3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified 1/		Group A subgroups	Limits		Unit
					Min	Max	
High level output voltage	V _{OH}	V _{IN} = V _{IH} or V _{IL} I _O ≤ 20 μA	V _{CC} = 2.0 V	1, 2, 3	1.9		V
			V _{CC} = 4.5 V		4.4		
			V _{CC} = 6.0 V		5.9		
		I _O ≤ 4.0 mA	V _{CC} = 4.5 V		3.7		
			V _{CC} = 6.0 V		5.2		
Low level output voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL} I _O ≤ 20 μA	V _{CC} = 2.0 V	1, 2, 3		0.1	V
			V _{CC} = 4.5 V			0.1	
			V _{CC} = 6.0 V			0.1	
		I _O ≤ 4.0 mA	V _{CC} = 4.5 V			0.4	
			V _{CC} = 6.0 V			0.4	
High level input voltage	V _{IH}	2/	V _{CC} = 2.0 V	1, 2, 3	1.5		V
			V _{CC} = 4.5 V		3.15		
			V _{CC} = 6.0 V		4.2		
Low level input voltage	V _{IL}	2/	V _{CC} = 2.0 V	1, 2, 3		0.3	V
			V _{CC} = 4.5 V			0.9	
			V _{CC} = 6.0 V			1.2	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C unless otherwise specified 1/	Group A subgroups	Limits		Unit
				Min	Max	
Input capacitance	C _{IN}	V _{IN} = 0 V T _C = +25°C See 4.3.1c	4		10	pF
Quiescent current	I _{CC}	V _{CC} = 6.0 V _{IN} = V _{CC} or GND	1, 2, 3		80	μA
Input leakage current	I _{IN}	V _{CC} = 6.0 V _{IN} = V _{CC} or GND	1, 2, 3		±1	μA
Functional tests		See 4.3.1d	7			
Propagation delay DATA to Q 3/	t _{PHL1} , t _{PLH1}	T _C = +25°C C _L = 50 pF ±10% See figure 3	9		125	ns
					25	
					24	
		T _C = -55°C, +125°C C _L = 50 pF ±10% See figure 3	10, 11		190	ns
					38	
					32	
		T _C = +25°C C _L = 50 pF ±10% See figure 3	9		130	ns
					25	
					21	
Propagation delay DATA to Q̄ 3/	t _{PHL2} , t _{PLH2}	T _C = -55°C, +125°C C _L = 50 pF ±10% See figure 3	10, 11		195	ns
					39	
					33	
		T _C = +25°C C _L = 50 pF ±10% See figure 3	9		130	ns
					25	
					21	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C unless otherwise specified 1/		Group A subgroups	Limits		Unit
					Min	Max	
Propagation delay ENABLE to Q 8/	t _{PHL3} , t _{PLH3}	T _C = +25°C C _L = 50 pF ±10% See figure 3	V _{CC} = 2.0 V	9		145	ns
			V _{CC} = 4.5 V			29	
			V _{CC} = 6.0 V			25	
		T _C = -55°C, +125°C C _L = 50 pF ±10% See figure 3	V _{CC} = 2.0 V	10, 11		220	ns
			V _{CC} = 4.5 V			44	
			V _{CC} = 6.0 V			38	
Propagation delay ENABLE to Q 3/	t _{PHL4} , t _{PLH4}	T _C = +25°C C _L = 50 pF ±10% See figure 3	V _{CC} = 2.0 V	9		145	ns
			V _{CC} = 4.5 V			29	
			V _{CC} = 6.0 V			26	
		T _C = -55°C, +125°C C _L = 50 pF ±10% See figure 3	V _{CC} = 2.0 V	10, 11		220	ns
			V _{CC} = 4.5 V			44	
			V _{CC} = 6.0 V			38	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C unless otherwise specified 1/	Group A subgroups	Limits		Unit
				Min	Max	
Transition time 4/	t _{TLH} , t _{THL}	T _C = +25°C C _L = 50 pF ±10% See figure 3	9		75	ns
					15	
					13	
		T _C = -55°C, +125°C C _L = 50 pF ±10% See figure 3	10, 11		110	ns
					22	
					19	

1/ For a power supply of 5 V ±10 percent, the worst case output voltages (V_{OH} and V_{OL}) occur for HC at 4.5 V. Thus the 4.5 V values should be used when designing with this supply. Worst case V_{IH} and V_{IL} occur at V_{CC} = 5.5 V and 4.5 V respectively. (The V_{IH} value at 5.5 V is 3.85 V.) The worst case leakage current (I_{IN}, I_{CC}, and I_{OZ}) occur for CMOS at the higher voltage and so the 6.0 V values should be used. Power dissipation capacitance (C_{PD}), typically 40 pF, determines the no load dynamic power consumption, P_D = C_{PD} V_{CC} 2 f + I_{CC} V_{CC}, and the no load dynamic current consumption, I_S = C_{PD} V_{CC} f + I_{CC}.

2/ Test not required if applied as a forcing function for V_{OH} and V_{OL}.

3/ AC testing at V_{CC} = 2.0 V and V_{CC} = 6.0 V shall be guaranteed if not tested to the specified parameters.

4/ Transition times, (t_{TLH}, t_{THL}), if not tested, shall be guaranteed to the specified parameters.

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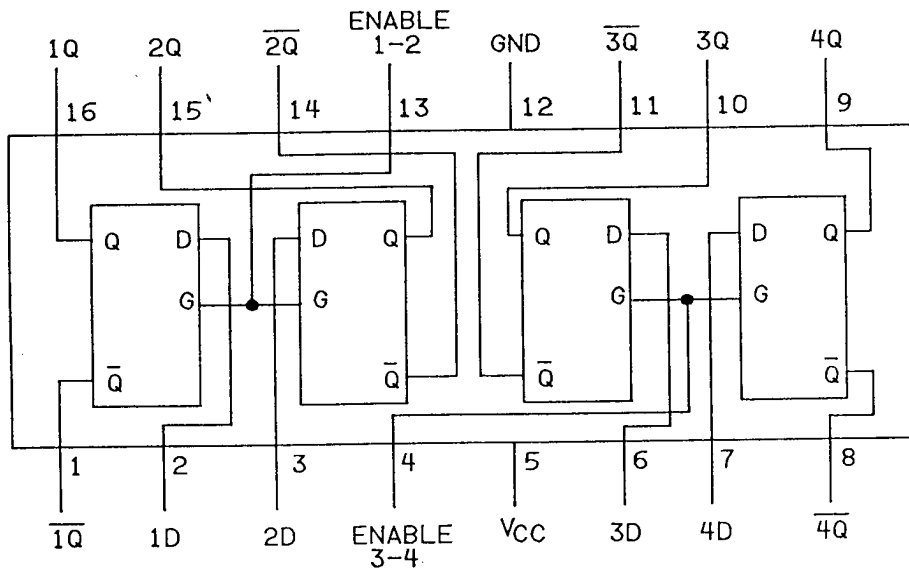
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Device type 01

Cases E and F



Case 2

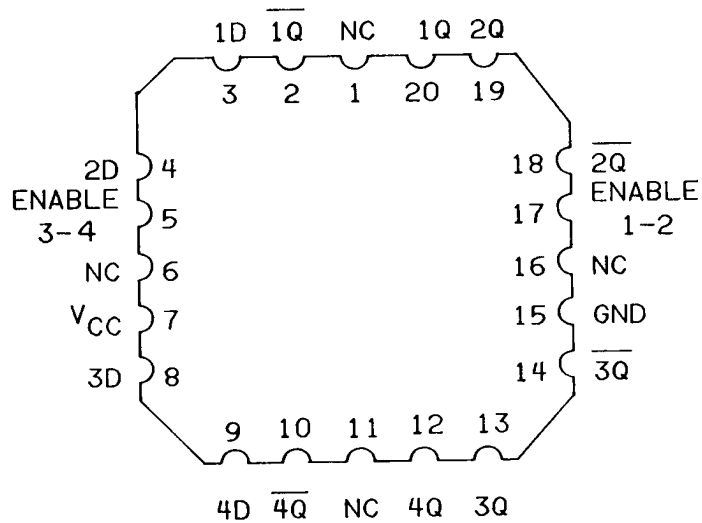


FIGURE 1. Terminal connections (top view).

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Inputs		Outputs	
D	G	Q	$\bar{Q}$
L	H	L	H
H	H	H	L
X	L	Q_0	$\bar{Q}_0$

H = High level
 L = Low level
 X = Don't care
 Q_0 = The level of Q before the transition of G

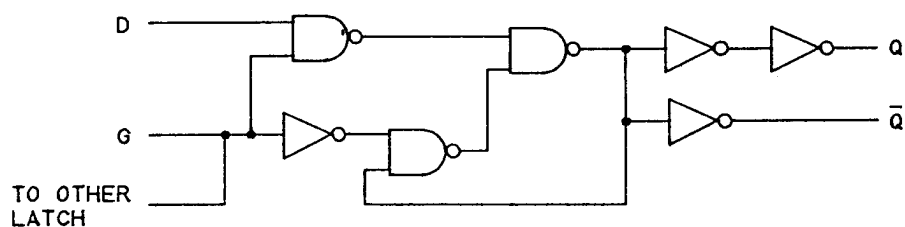


FIGURE 2. Truth table and logic diagram.

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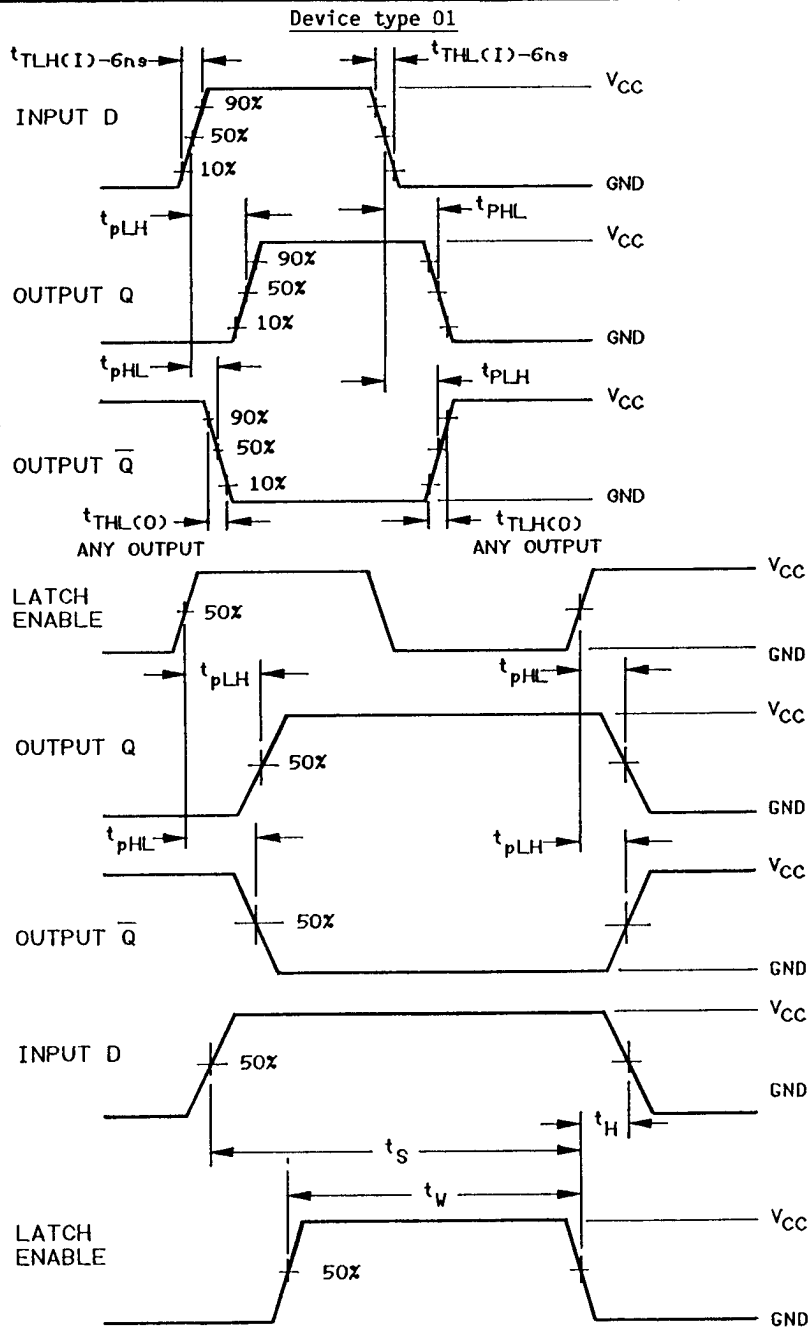


FIGURE 3. Switching waveforms.

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4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroup 4 (C_{IN} measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance.
- d. Subgroup 7 sufficient to verify the function table.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*, 2, 9
Group A test requirements (method 5005)	1, 2, 3, 4, 7, 9, 10, 11**
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroup 1.

** Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Replaceability is determined as follows:

- Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/65401B---.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4. Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1/</u>	Replacement military specification part number
8407001EX	01295 04713 18714 27014	SNJ54HC75J 54HC75/BEAJC CD54HC75F/3A MM54HC75J/883	M38510/65401BEX
8407001FX	01295	SNJ54HC75W	M38510/65401BFX
84070012X	04713 27014	54HC75M/B2CJC MM54HC75E/883	M38510/65401B2X

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

01295

04713

18714

27014

Vender name and address

Texas Instruments, Inc.
P.O. Box 6448
Midland, TX 79701

Motorola, Inc.
7402 S. Price Rd.
Tempe, AZ 85283

RCA Corporation
Route 202
Somerville, NJ 08876

National Semiconductor
2900 Semiconductor Dr.
Santa Clara, CA 95051

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